

# FOREIGN PATENT DOCUMENTS

Examiner Initial	+/*	Document Number	Date	Name	Class	SubClass	Filing Date If Appropriate
FHD		EP 035-271 A1	09-Sep-81				
FHD	+	JP 01236516 A	21-Sep-89	Watanabe Kiyoshi et al			16-Mar-88
FHD		JP 56-092946A	28-Jul-81	Japan (English Lanugage Abstract			
FHD		JP 56-109404A	29-Aug-81	Japan (with English Language Abst			
FHD	+	JP 60147452 A	03-Aug-85	Watanabe Kiyoshi et al			11-Jan-84

## OTHER DOCUMENTS (Including Authors, title, Date, Pertinent Papers, etc.)

Examiner Initial	+/*	Document Cite
FHD		Penuzzotti, F. et al, IEEE Annual Report Conference on Electrical Insulation and Dielectric Phenomena, San Francisco, CA. (Oct 20-23, 1996) pp 48-51
FHD	+	Rosen, P., et al, IEEE Transactions on Dielectrics and Electrical Insulation, 5:189-194 (1998)
FHD		Wartusch, J, Conf. Rec IEEE International Symposium Electr. Insul. (1980) 216-221

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